

General Description:

The HMD4006AS uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge and operation with gate voltage as low as 4.5V. It can be used in a wide variety of applications. The package form is SOP-8, which accords with the RoHS standard and Halogen Free standard.

Features:

- Fast Switching
- Low Gate Charge and $R_{DS(on)}$
- Low Reverse transfer capacitances

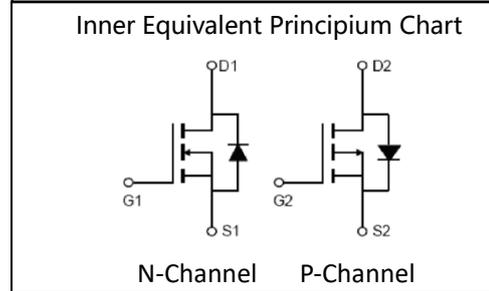
Applications:

- Battery switching application
- Hard switched and high frequency circuits
- Power management

Package Marking and Ordering Information:

Device Marking	Device	Device Package	Quantity
D4006AS	HMD4006AS	SOP-8	4000 units

PMOS	V_{DSS}	-40	V
	I_D	-5.5	A
	$R_{DS(ON)TYPE}$	42	m Ω
NMOS	V_{DSS}	40	V
	I_D	6.5	A
	$R_{DS(ON)TYPE}$	24	m Ω



Absolute Maximum Ratings (TA= 25°C unless otherwise specified):

Symbol	Parameter	NMOS	PMOS	Units
V_{DSS}	Drain-to-Source Voltage	40	-40	V
I_D	Continuous Drain Current	6.5	-5.5	A
I_{DM}^{a1}	Pulsed Drain Current	-26	-22	A
V_{GS}	Gate-to-Source Voltage	± 20	± 20	V
P_D	Power Dissipation	2	2	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150		$^{\circ}C$
T_L	Maximum Temperature for Soldering	300		$^{\circ}C$

N-MOS Electrical Characteristics (T_c= 25°C unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	40	--	--	V
ΔBV _{DSS} /ΔT _J	BVD _{SS} Temperature Coefficient	I _D =250uA, Reference 25°C	--	0.1	--	V/°C
I _{DSS}	Drain to Source Leakage Current	V _{DS} = 40V, V _{GS} = 0V, T _j = 25°C	--	--	1	μA
		V _{DS} = 40V, V _{GS} = 0V, T _j = 55°C	--	--	5	
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} = +20V	--	--	100	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} = -20V	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =5A	--	24.0	28.0	mΩ
		V _{GS} =4.5V, I _D =3A	--	28.0	36.0	
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	1.0	1.5	1.9	V
Pulse width tp ≤ 380μs, δ ≤ 2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
C _{iss}	Input Capacitance	V _{GS} = 0V	--	750	--	pF
C _{oss}	Output Capacitance	V _{DS} = 20V	--	150	--	
C _{rss}	Reverse Transfer Capacitance	f = 1.0MHz	--	80	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D = 5A	--	6.0	--	ns
t _r	Rise Time	V _{DS} = 20V	--	36.0	--	
t _{d(OFF)}	Turn-Off Delay Time	V _{GS} = 10V	--	29.0	--	
t _f	Fall Time	R _G = 3.0Ω R _L = 1.0Ω	--	7.0	--	
Q _g	Total Gate Charge	I _D = 5A	--	15	--	nC
Q _{gs}	Gate to Source Charge	V _{DD} = 20V	--	3	--	
Q _{gd}	Gate to Drain ("Miller") Charge	V _{GS} = 10V	--	2.5	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	5	A
V_{SD}	Diode Forward Voltage	$I_S=5A, V_{GS}=0V$	--	0.85	1.2	V
t_{rr}	Reverse Recovery Time	$I_S=5A, T_j = 25^\circ$	--	40	--	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt=100A/\mu s,$ $V_{GS}=0V$	--	21	--	nC
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

P-MOS Electrical Characteristics ($T_c = 25^\circ C$ unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-40	--	--	V
I_{DSS}	Drain to Source Leakage Current	$V_{DS} = -40V, V_{GS}= 0V$	--	--	-1	μA
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS} = +20V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = -20V$	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)1}$	Drain-to-Source On-Resistance	$V_{GS}=-10V, I_D=-5A$	--	42	50	$m\Omega$
$R_{DS(ON)2}$	Drain-to-Source On-Resistance	$V_{GS}=-4.5V, I_D=-3A$	--	51	72	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1.2	-1.65	-2.0	V

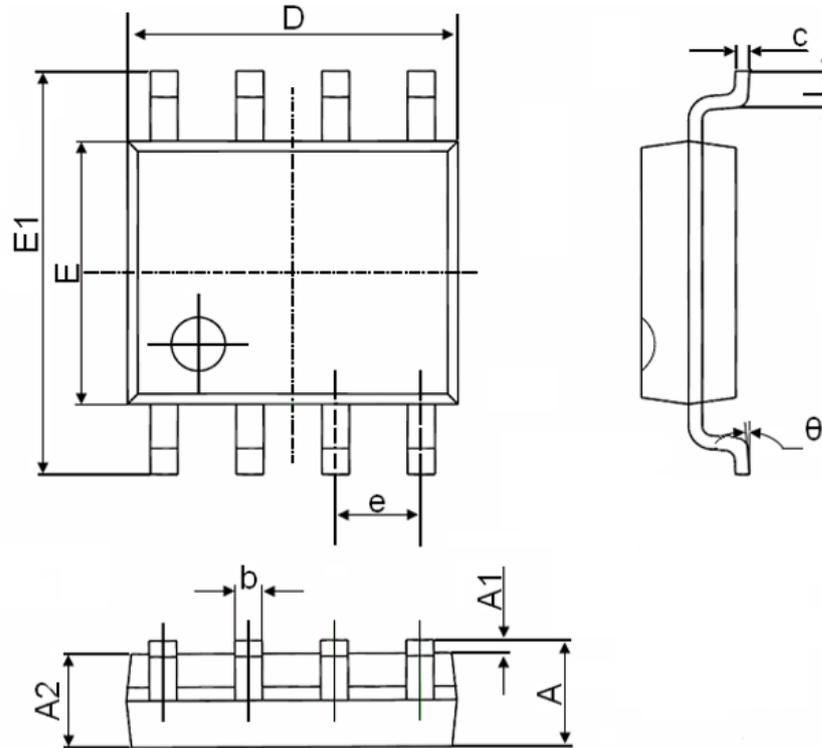
Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
C_{iss}	Input Capacitance	$V_{GS} = 0V$	--	1450	--	pF
C_{oss}	Output Capacitance	$V_{DS} = -20V$	--	175	--	
C_{rss}	Reverse Transfer Capacitance	$f = 1.0MHz$	--	150	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = -5A$	--	5	--	ns
t_r	Rise Time	$V_{DS} = -20V$	--	8.5	--	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS} = -10V$	--	18	--	
t_f	Fall Time	$R_G = 3.0\Omega$	--	11	--	
Q_g	Total Gate Charge	$I_D = -5A$	--	33	--	nC
Q_{gs}	Gate to Source Charge	$V_{DS} = -20V$	--	7	--	
Q_{gd}	Gate to Drain ("Miller") Charge	$V_{GS} = -10V$	--	7.5	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Diode Forward Current		--	--	-5	A
V_{SD}	Diode Forward Voltage	$I_S = -5A, V_{GS} = 0V$	--	--	-1.2	V

Symbol	Parameter	Typ.	Units
$R_{\theta JA}$	Junction-to-Ambient	40	$^{\circ}C/W$

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

Package Information


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°

Revision History

Revision	Date	Descriptions
REV.1.0	Mar., 2023	Initial Version